# Atomic Layer Deposition at ASU NanoFab

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### **Current ALD Capability**

- Cambridge Nanotech Savannah one unit
- Available chemical precursors
  - Trimethyl Aluminum (Al<sub>2</sub>O<sub>3</sub>)
  - Diethylene Zinc (ZnO<sub>2</sub>)
  - Tetrakis (dimethlamino) Hafnium(HfO<sub>2</sub>)
- First film (Al<sub>2</sub>O<sub>3</sub>) deposited on 9/27/2012
  c/o J Provine & M. Rincon (Stanford)
   Growth rate 0.88 Å/cycle (15 ms dose)
- HfO2 deposition (10 ms dose)
  - Growth rate 0.95 Å/cycle



#### Al<sub>2</sub>O<sub>3</sub> Growth Rate



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### **Equipment Issues**

- TDMA- Hf pre-cursor needs heater jacket at 75 °C
  - Always have to enter this set point thru GUI otherwise heater doesn't come on
- We have APS UPS and every time we login we get the following dialog box
  - "Do you want to allow the following program to make changes to this computer?"
- After launching the tool software, we frequently get the following error
  - USB ERROR/From Command: MPUSBWrite/Called from Savannah.vi
  - Power cycling the circuit breakers on the front of the tool rectifies this error?
- One run aborted during a Windows update
  - Is this common?
- Over pressure abort (> 1 Torr) when we first ran HfO<sub>2</sub>
  - Reducing the dose from 15 ms to 10 ms fixed the problem
  - But this value is faster than the valve can operate?
- Cambridge Nanotech support
  - No response to email sent 11/19/2012 and web site access denied.....
- Equipment Usage Level
  - very low % since we're still evaluating the tool

## **Future Plans**

- Film characterization thickness is relative since based on pre-existing optical models loaded in Woollam ellipsometer
  - Refractive index (need to determine independently)
- Thin Al<sub>2</sub>O<sub>3</sub> hard mask for nanolithography application
  - Preliminary RIE (Cl/Ar) sputter etch data of 20 nm/min vs. 120 nm/min for PMMA is promising.
- Looking to add TiO<sub>2</sub> capability in the near future
- Proposal has been submitted for GdO<sub>2</sub>, Ta<sub>2</sub>O<sub>5</sub>, and WO<sub>3</sub>
  - Application as dielectric stack for programmable memory cells